

<b>Notice of References Cited</b>	Application/Control No. 10/762,330	Applicant(s)/Patent Under Reexamination TANAKA, SATORU	
	Examiner BENJAMIN E. LANIER	Art Unit 2432	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0129264 A1	09-2002	Rowland et al.	713/200
	B	US-			
	C	US-			
	D	US-			
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**FOREIGN PATENT DOCUMENTS**

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